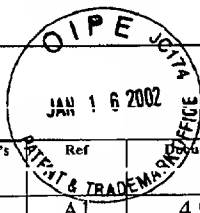


INFORMATION DISCLOSURE 1449	Docket No.: MCA-400 PC/US	Application No.: 09/889,901
	Applicant: Yen, et al.	
	Filing Date: July 24, 2001	Group Art Unit: 1723



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* Examiner's Index	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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RM	*B2	EP 0 175 432	03/86	EPO				
	B3	EP 0 217 482	04/87	EPO				
	*B4	EP 0 299 459	01/89	EPO				
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Examiner:

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Date Considered:

8/22/03

Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant

\* Indicates a cite that has been previously forwarded to the USPTO and is not enclosed.